# Notice of References Cited

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09/766,046

cant(s)/Patent Under Reexam Ramdani et al.

Examiner

B. William Baumeister

Art Unit 2815

Page 1 of 2

### U.S. PATENT DOCUMENTS

		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification <sup>2</sup>
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## FOREIGN PATENT DOCUMENTS

	Document Number Country Code-Number-Kind Code	Date MM-YYYY¹	Country	Name	Classification <sup>2</sup>
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s					
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#### **NON-PATENT DOCUMENTS**

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
υ	Kaushik, "Device Characteristics of Crystalline Epitaxial Oxides on Silicon," 58th Annual Device Research Conference June 19-21, 2000, pp. 17-20.
 v	Eisenbeiser et al., Field effect transistors with SrTiOs gate dielectric on Si," 6 March 2000, Applied Physics Letters, Vol. 76, No. 10, pp. 1324-1326.
 w	Weiss, "Speed demon gets hooked on silicon," Science News Online, 9/15/2001.
x	"Motorola develops new super-fast chip," USA Today, 9/4/2001.

<sup>\*</sup> A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).

<sup>&</sup>lt;sup>2</sup> Classifications may be U.S. or foreign.

# ₩Notice of References Cited

Application/Control No.	Applicant(s)/Patent Under Reexam		
09/766,046	Ramdani et al.		
Examiner	Art Unit		
B. William Baumeister	2815	Page 2 of 2	

## U.S. PATENT DOCUMENTS

Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>
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### FOREIGN PATENT DOCUMENTS

	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Country	Name	Classification <sup>2</sup>
N					
0					
Р					
Q					
R					
s					
Т					

### **NON-PATENT DOCUMENTS**

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
υ	Valigra, "Motorola Lays GaAs on Si Wafer," AsiaBiz Tech, Nov: 2001.
v	"Holy Grail! Motorola claims high-yield GaAs breakthrough," Micromagazine.com (no date available).
w	
x	

<sup>\*</sup> A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).

<sup>&</sup>lt;sup>2</sup> Classifications may be U.S. or foreign.